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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I ² C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	20
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 12x14b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	24-VFQFN Exposed Pad
Supplier Device Package	24-QFN (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8lb10f16es0-b-qfn24

1. Feature List

The EFM8LB1 device family are fully integrated, mixed-signal system-on-a-chip MCUs. Highlighted features are listed below.

- Core:
 - Pipelined CIP-51 Core
 - Fully compatible with standard 8051 instruction set
 - 70% of instructions execute in 1-2 clock cycles
 - 72 MHz maximum operating frequency
- Memory:
 - Up to 64 kB flash memory (63 kB user-accessible), in-system re-programmable from firmware in 512-byte sectors
 - Up to 4352 bytes RAM (including 256 bytes standard 8051 RAM and 4096 bytes on-chip XRAM)
- Power:
 - Internal LDO regulator for CPU core voltage
 - Power-on reset circuit and brownout detectors
- I/O: Up to 29 total multifunction I/O pins:
 - Up to 25 pins 5 V tolerant under bias
 - Selectable state retention through reset events
 - Flexible peripheral crossbar for peripheral routing
 - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
 - Internal 72 MHz oscillator with accuracy of $\pm 2\%$
 - Internal 24.5 MHz oscillator with $\pm 2\%$ accuracy
 - Internal 80 kHz low-frequency oscillator
 - External CMOS clock option
 - External crystal/RC oscillator (up to 25 MHz)
- Analog:
 - 14/12/10-Bit Analog-to-Digital Converter (ADC)
 - Internal calibrated temperature sensor ($\pm 3\text{ }^{\circ}\text{C}$)
 - 4 x 12-Bit Digital-to-Analog Converters (DAC)
 - 2 x Low-current analog comparators with adjustable reference
- Communications and Digital Peripherals:
 - 2 x UART, up to 3 Mbaud
 - SPI™ Master / Slave, up to 12 Mbps
 - SMBus™/I2C™ Master / Slave, up to 400 kbps
 - I2C High-Speed Slave, up to 3.4 Mbps
 - 16-bit CRC unit, supporting automatic CRC of flash at 256-byte boundaries
 - 4 Configurable Logic Units
- Timers/Counters and PWM:
 - 6-channel Programmable Counter Array (PCA) supporting PWM, capture/compare, and frequency output modes
 - 6 x 16-bit general-purpose timers
 - Independent watchdog timer, clocked from the low frequency oscillator
- On-Chip, Non-Intrusive Debugging
 - Full memory and register inspection
 - Four hardware breakpoints, single-stepping
- Pre-programmed UART or SMBus bootloader

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8LB1 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing nonvolatile data storage and allowing field upgrades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. Device operation is specified from 2.2 V up to a 3.6 V supply. Devices are AEC-Q100 qualified (pending) and available in 4x4 mm 32-pin QFN, 3x3 mm 24-pin QFN, 32-pin QFP, or 24-pin QSOP packages. All package options are lead-free and RoHS compliant.

3. System Overview

3.1 Introduction

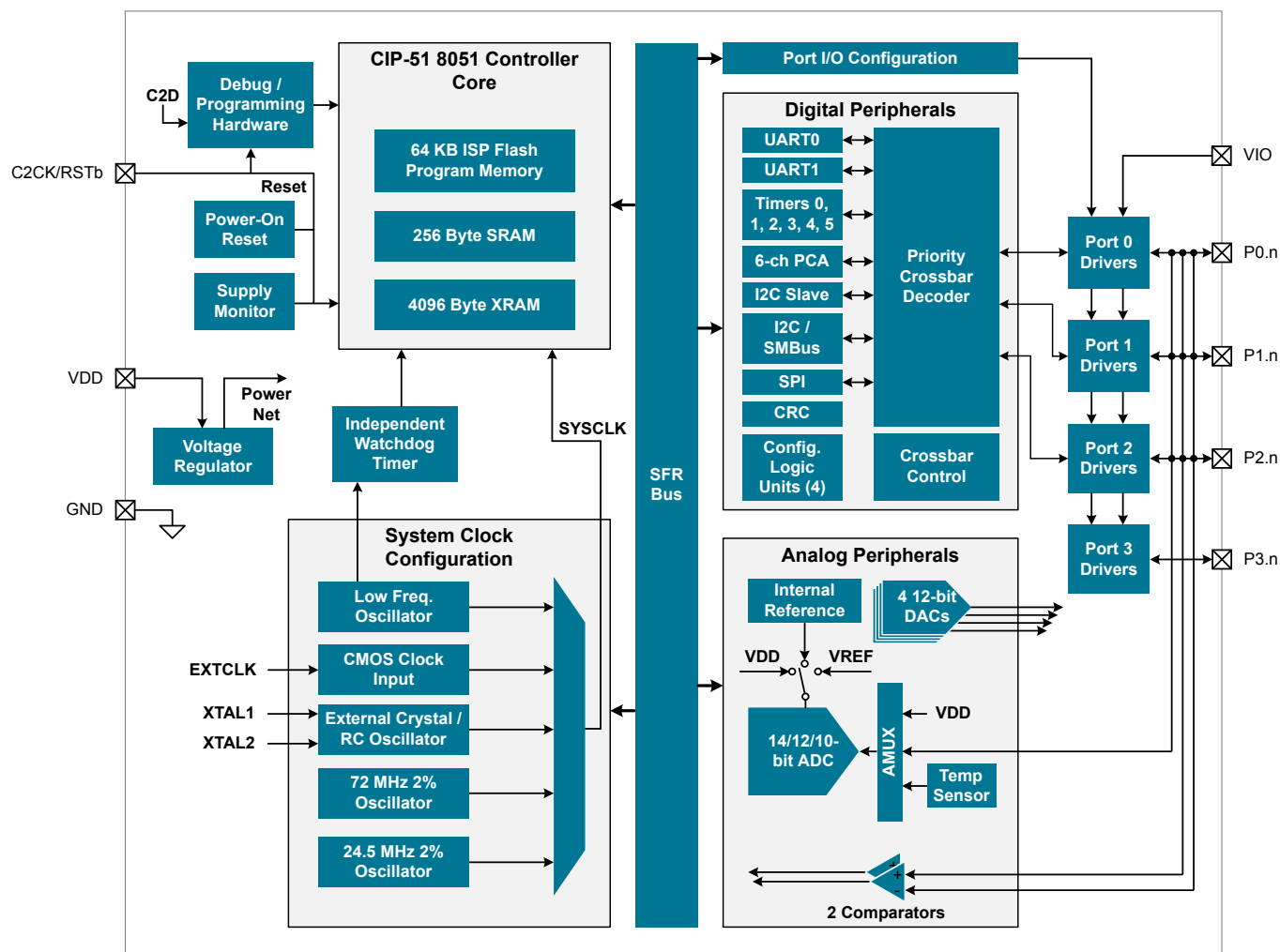


Figure 3.1. Detailed EFM8LB1 Block Diagram

3.4 Clocking

The CPU core and peripheral subsystem may be clocked by both internal and external oscillator resources. By default, the system clock comes up running from the 24.5 MHz oscillator divided by 8.

The clock control system offers the following features:

- Provides clock to core and peripherals.
- 24.5 MHz internal oscillator (HFOSC0), accurate to $\pm 2\%$ over supply and temperature corners.
- 72 MHz internal oscillator (HFOSC1), accurate to $\pm 2\%$ over supply and temperature corners.
- 80 kHz low-frequency oscillator (LFOSC0).
- External RC, CMOS, and high-frequency crystal clock options (EXTCLK).
- Clock divider with eight settings for flexible clock scaling:
 - Divide the selected clock source by 1, 2, 4, 8, 16, 32, 64, or 128.
 - HFOSC0 and HFOSC1 include 1.5x pre-scalers for further flexibility.

3.5 Counters/Timers and PWM

Programmable Counter Array (PCA0)

The programmable counter array (PCA) provides multiple channels of enhanced timer and PWM functionality while requiring less CPU intervention than standard counter/timers. The PCA consists of a dedicated 16-bit counter/timer and one 16-bit capture/compare module for each channel. The counter/timer is driven by a programmable timebase that has flexible external and internal clocking options. Each capture/compare module may be configured to operate independently in one of five modes: Edge-Triggered Capture, Software Timer, High-Speed Output, Frequency Output, or Pulse-Width Modulated (PWM) Output. Each capture/compare module has its own associated I/O line (CEXn) which is routed through the crossbar to port I/O when enabled.

- 16-bit time base
- Programmable clock divisor and clock source selection
- Up to six independently-configurable channels
- 8, 9, 10, 11 and 16-bit PWM modes (center or edge-aligned operation)
- Output polarity control
- Frequency output mode
- Capture on rising, falling or any edge
- Compare function for arbitrary waveform generation
- Software timer (internal compare) mode
- Can accept hardware “kill” signal from comparator 0 or comparator 1

3.7 Analog

14/12/10-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 14-, 12-, and 10-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 20 external inputs
- Single-ended 14-bit, 12-bit and 10-bit modes
- Supports an output update rate of up to 1 Msps in 12-bit mode
- Channel sequencer logic with direct-to-XDATA output transfers
- Operation in a low power mode at lower conversion speeds
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Output data window comparator allows automatic range checking
- Support for output data accumulation
- Conversion complete and window compare interrupts supported
- Flexible output data formatting
- Includes a fully-internal fast-settling 1.65 V reference and an on-chip precision 2.4 / 1.2 V reference, with support for using the supply as the reference, an external reference and signal ground
- Integrated factory-calibrated temperature sensor

12-Bit Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3)

The DAC modules are 12-bit Digital-to-Analog Converters with the capability to synchronize multiple outputs together. The DACs are fully configurable under software control. The voltage reference for the DACs is selectable between internal and external reference sources.

- Voltage output with 12-bit performance
- Hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Outputs may be configured to persist through reset and maintain output state to avoid system disruption
- Multiple DAC outputs can be synchronized together
- DAC pairs (DAC0 and 1 or DAC2 and 3) support complementary output waveform generation
- Outputs may be switched between two levels according to state of configurable logic / PWM input trigger
- Flexible input data formatting
- Supports references from internal supply, on-chip precision reference, or external VREF pin

Low Current Comparators (CMP0, CMP1)

An analog comparator is used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 9 (CMP1) external positive inputs
- Up to 10 (CMP0) or 9 (CMP1) external negative inputs
- Additional input options:
 - Internal connection to LDO output
 - Direct connection to GND
 - Direct connection to VDD
 - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and ± 20 mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in [Table 4.1 Recommended Operating Conditions on page 14](#), unless stated otherwise.

4.1.1 Recommended Operating Conditions

Table 4.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Operating Supply Voltage on VDD	V _{DD}		2.2	—	3.6	V
Operating Supply Voltage on VIO ^{2, 3}	V _{IO}		2.2	—	V _{DD}	V
System Clock Frequency	f _{SYSCLK}		0	—	73.5	MHz
Operating Ambient Temperature	T _A		-40	—	105	°C

Note:

1. All voltages with respect to GND
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.
3. GPIO levels are undefined whenever VIO is less than 1 V.

4.1.3 Reset and Supply Monitor

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
VDD Supply Monitor Threshold	V _{VDDM}		1.95	2.05	2.15	V
Power-On Reset (POR) Threshold	V _{POR}	Rising Voltage on VDD	—	1.4	—	V
		Falling Voltage on VDD	0.75	—	1.36	V
VDD Ramp Time	t _{RMP}	Time to V _{DD} > 2.2 V	10	—	—	μs
Reset Delay from POR	t _{POR}	Relative to V _{DD} > V _{POR}	3	10	31	ms
Reset Delay from non-POR source	t _{RST}	Time between release of reset source and code execution	—	50	—	μs
RST Low Time to Generate Reset	t _{RSTL}		15	—	—	μs
Missing Clock Detector Response Time (final rising edge to reset)	t _{MCD}	F _{SYSClk} > 1 MHz	—	0.625	1.2	ms
Missing Clock Detector Trigger Frequency	F _{MCD}		—	7.5	13.5	kHz
VDD Supply Monitor Turn-On Time	t _{MON}		—	2	—	μs

4.1.4 Flash Memory

Table 4.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time ^{1,2}	t _{WRITE}	One Byte, F _{SYSClk} = 24.5 MHz	19	20	21	μs
Erase Time ^{1,2}	t _{ERASE}	One Page, F _{SYSClk} = 24.5 MHz	5.2	5.35	5.5	ms
V _{DD} Voltage During Programming ³	V _{PROG}		2.2	—	3.6	V
Endurance (Write/Erase Cycles)	N _{WE}		20k	100k	—	Cycles
CRC Calculation Time	t _{CRC}	One 256-Byte Block SYSClk = 48 MHz	—	5.5	—	μs

Note:

- Does not include sequencing time before and after the write/erase operation, which may be multiple SYSClk cycles.
- The internal High-Frequency Oscillator 0 has a programmable output frequency, which is factory programmed to 24.5 MHz. If user firmware adjusts the oscillator speed, it must be between 22 and 25 MHz during any flash write or erase operation. It is recommended to write the HFO0CAL register back to its reset value when writing or erasing flash.
- Flash can be safely programmed at any voltage above the supply monitor threshold (V_{VDDM}).
- Data Retention Information is published in the Quarterly Quality and Reliability Report.

4.1.7 External Clock Input

Table 4.7. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	50	MHz
External Input CMOS Clock High Time	t_{CMOSH}		9	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		9	—	—	ns

4.1.8 Crystal Oscillator

Table 4.8. Crystal Oscillator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal Frequency	f_{XTAL}		0.02	—	25	MHz
Crystal Drive Current	I_{XTAL}	XFCN = 0	—	0.5	—	μA
		XFCN = 1	—	1.5	—	μA
		XFCN = 2	—	4.8	—	μA
		XFCN = 3	—	14	—	μA
		XFCN = 4	—	40	—	μA
		XFCN = 5	—	120	—	μA
		XFCN = 6	—	550	—	μA
		XFCN = 7	—	2.6	—	mA

4.1.9 ADC

Table 4.9. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N _{bits}	14 Bit Mode	14			Bits
		12 Bit Mode	12			Bits
		10 Bit Mode	10			Bits
Throughput Rate (High Speed Mode)	f _S	14 Bit Mode	—	—	900	ksps
		12 Bit Mode	—	—	1	Msps
		10 Bit Mode	—	—	1.125	Msps
Throughput Rate (Low Power Mode)	f _S	14 Bit Mode	—	—	320	ksps
		12 Bit Mode	—	—	340	ksps
		10 Bit Mode	—	—	360	ksps
Tracking Time	t _{TRK}	High Speed Mode	217.8 ¹	—	—	ns
		Low Power Mode	450	—	—	ns
Power-On Time	t _{PWR}		1.2	—	—	μs
SAR Clock Frequency	f _{SAR}	High Speed Mode	—	—	18.36	MHz
		Low Power Mode	—	—	12.25	MHz
Conversion Time ²	t _{CNV}	14-Bit Conversion, SAR Clock = 18 MHz, System Clock = 72 MHz.	0.81			μs
		12-Bit Conversion, SAR Clock = 18 MHz, System Clock = 72 MHz.	0.7			μs
		10-Bit Conversion, SAR Clock = 18 MHz, System Clock = 72 MHz.	0.59			μs
Sample/Hold Capacitor	C _{SAR}	Gain = 1	—	5.2	—	pF
		Gain = 0.75	—	3.9	—	pF
		Gain = 0.5	—	2.6	—	pF
		Gain = 0.25	—	1.3	—	pF
Input Pin Capacitance	C _{IN}	High Quality Input	—	20	—	pF
		Normal Input	—	20	—	pF
Input Mux Impedance	R _{MUX}	High Quality Input	—	330	—	Ω
		Normal Input	—	550	—	Ω
Voltage Reference Range	V _{REF}		1	—	V _{IO}	V
Input Voltage Range ³	V _{IN}		0	—	V _{REF} / Gain	V

4.1.11 Temperature Sensor

Table 4.11. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Uncalibrated Offset	V_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	751	—	mV
Uncalibrated Offset Error ¹	E_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	19	—	mV
Slope	M		—	2.82	—	mV/ $^{\circ}\text{C}$
Slope Error ¹	E_M		—	29	—	$\mu\text{V}/^{\circ}\text{C}$
Linearity	LIN	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	—	-0.1 to 0.15	—	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	—	-0.2 to 0.35	—	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	—	-0.4 to 0.8	—	$^{\circ}\text{C}$
Turn-on Time	t_{ON}		—	3.5	—	μs
Temp Sensor Error Using Typical Slope and Factory-Calibrated Offset ^{2, 3}	E_{TOT}	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	-2.6	—	1.8	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	-2.9	—	2.7	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	-3.2	—	4.2	$^{\circ}\text{C}$

Note:

1. Represents one standard deviation from the mean.
2. The factory-calibrated offset value is stored in the read-only area of flash in locations 0xFFD4 (low byte) and 0xFFD5 (high byte). The 14-bit result represents the output of the ADC when sampling the temp sensor using the 1.65 V internal voltage reference.
3. The temp sensor error includes the offset calibration error, slope error, and linearity error. The values are based upon characterization and are not tested across temperature in production. The values represent three standard deviations above and below the mean. Additional information on achieving high measurement accuracy is available in AN929: Accurate Temperature Sensing with the EFM8 Laser Bee MCU Family.

4.1.13 Comparators

Table 4.13. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential	—	100	—	ns
		-100 mV Differential	—	150	—	ns
Response Time, CPMD = 11 (Low- est Power)	t_{RESP3}	+100 mV Differential	—	1.5	—	μs
		-100 mV Differential	—	3.5	—	μs
Positive Hysteresis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysteresis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	-8	—	mV
		CPHYN = 10	—	-16	—	mV
		CPHYN = 11	—	-32	—	mV
Positive Hysteresis Mode 1 (CPMD = 01)	HYS_{CP+}	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysteresis Mode 1 (CPMD = 01)	HYS_{CP-}	CPHYN = 00	—	-0.5	—	mV
		CPHYN = 01	—	-6	—	mV
		CPHYN = 10	—	-12	—	mV
		CPHYN = 11	—	-24	—	mV
Positive Hysteresis Mode 2 (CPMD = 10)	HYS_{CP+}	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysteresis Mode 2 (CPMD = 10)	HYS_{CP-}	CPHYN = 00	—	-0.6	—	mV
		CPHYN = 01	—	-4.5	—	mV
		CPHYN = 10	—	-9	—	mV
		CPHYN = 11	—	-18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Negative Hysteresis Mode 3 (CPMD = 11)	HYS _{CP-}	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V _{IN}		-0.25	—	V _{IO} +0.25	V
Input Pin Capacitance	C _{CP}		—	7.5	—	pF
Internal Reference DAC Resolution	N _{bits}		6			bits
Common-Mode Rejection Ratio	CMRR _{CP}		—	70	—	dB
Power Supply Rejection Ratio	PSRR _{CP}		—	72	—	dB
Input Offset Voltage	V _{OFF}	T _A = 25 °C	-10	0	10	mV
Input Offset Tempco	TC _{OFF}		—	3.5	—	μV/°

4.1.14 Configurable Logic

Table 4.14. Configurable Logic

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Propagation Delay	t _{DLY}	Through single CLU Using an external pin	—	—	35.3	ns
		Through single CLU Using an internal connection	—	3	—	ns
Clocking Frequency	F _{CLK}	1 or 2 CLUs Cascaded	—	—	73.5	MHz
		3 or 4 CLUs Cascaded	—	—	36.75	MHz

4.3 Absolute Maximum Ratings

Stresses above those listed in [Table 4.19 Absolute Maximum Ratings on page 30](#) may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at <http://www.silabs.com/support/quality/pages/default.aspx>.

Table 4.19. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VIO ²	V_{IO}		GND-0.3	$V_{DD}+0.3$	V
Voltage on I/O pins or RSTb, excluding P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}	$V_{IO} > 3.3\text{ V}$	GND-0.3	5.8	V
		$V_{IO} < 3.3\text{ V}$	GND-0.3	$V_{IO}+2.5$	V
Voltage on P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}		GND-0.3	$V_{DD}+0.3$	V
Total Current Sunk into Supply Pin	I_{VDD}		—	400	mA
Total Current Sourced out of Ground Pin	I_{GND}		400	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA
Operating Junction Temperature	T_J	$T_A = -40\text{ °C to }105\text{ °C}$	-40	130	°C

Note:

1. Exposure to maximum rating conditions for extended periods may affect device reliability.
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
23	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12	ADC0.8 CMP0P.8 CMP0N.8
24	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.13	ADC0.7 CMP0P.7 CMP0N.7
25	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU1OUT CLU0A.12 CLU1A.10 CLU2A.10 CLU3B.12	ADC0.6 CMP0P.6 CMP0N.6 CMP1P.1 CMP1N.1
26	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.0 CMP1N.0
27	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4
28	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9 CLU3B.11	ADC0.3 CMP0P.3 CMP0N.3

6.2 EFM8LB1x-QFP32 Pin Definitions

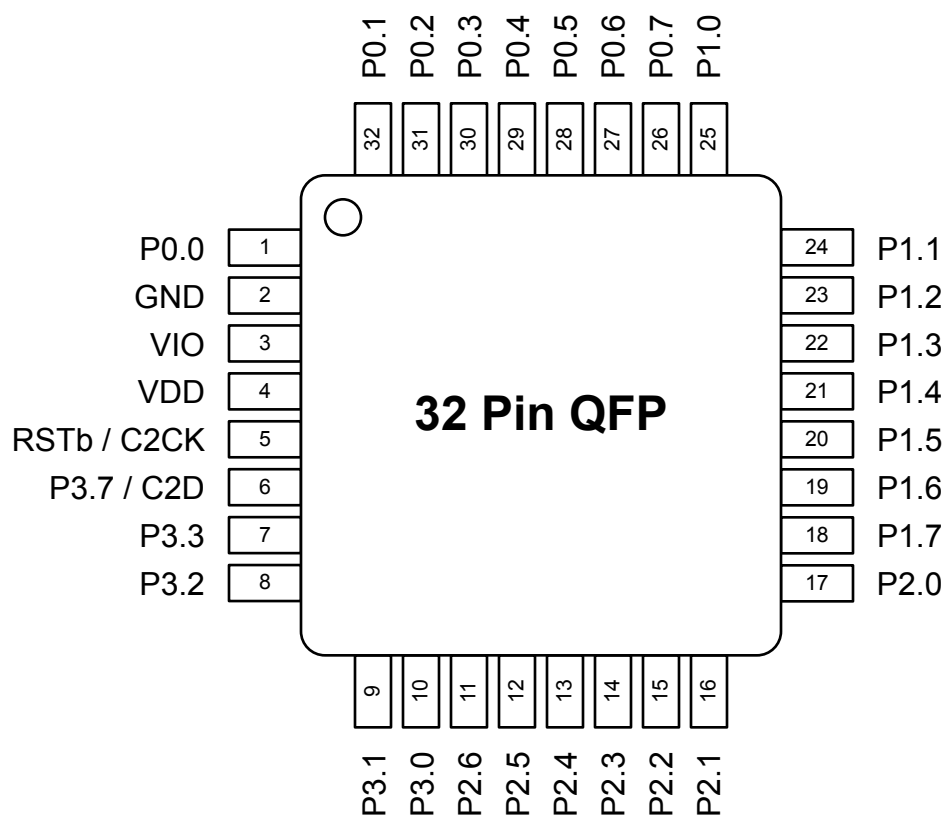


Figure 6.2. EFM8LB1x-QFP32 Pinout

Table 6.2. Pin Definitions for EFM8LB1x-QFP32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	GND	Ground			
3	VIO	I/O Supply Power Input			
4	VDD	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
25	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU1OUT CLU0A.12 CLU1A.10 CLU2A.10 CLU3B.12	ADC0.6 CMP0P.6 CMP0N.6 CMP1P.1 CMP1N.1
26	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.0 CMP1N.0
27	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4
28	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9 CLU3B.11	ADC0.3 CMP0P.3 CMP0N.3
29	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8 CLU3B.10	ADC0.2 CMP0P.2 CMP0N.2

7. QFN32 Package Specifications

7.1 QFN32 Package Dimensions

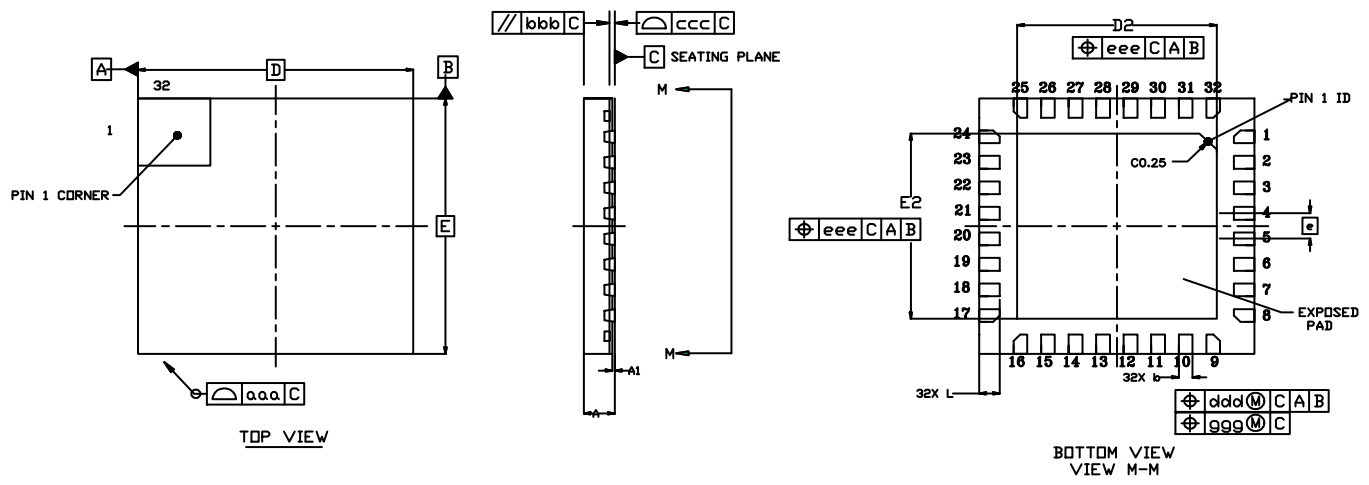


Figure 7.1. QFN32 Package Drawing

Table 7.1. QFN32 Package Dimensions

Dimension	Min	Typ	Max
A	0.45	0.50	0.55
A1	0.00	0.035	0.05
b	0.15	0.20	0.25
D	4.00 BSC.		
D2	2.80	2.90	3.00
e	0.40 BSC.		
E	4.00 BSC.		
E2	2.80	2.90	3.00
L	0.20	0.30	0.40
aaa	—	—	0.10
bbb	—	—	0.10
ccc	—	—	0.08
ddd	—	—	0.10
eee	—	—	0.10
ggg	—	—	0.05

8.3 QFP32 Package Marking

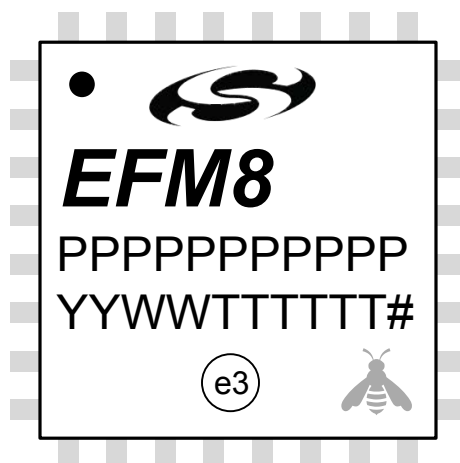


Figure 8.3. QFP32 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

9.2 QFN24 PCB Land Pattern

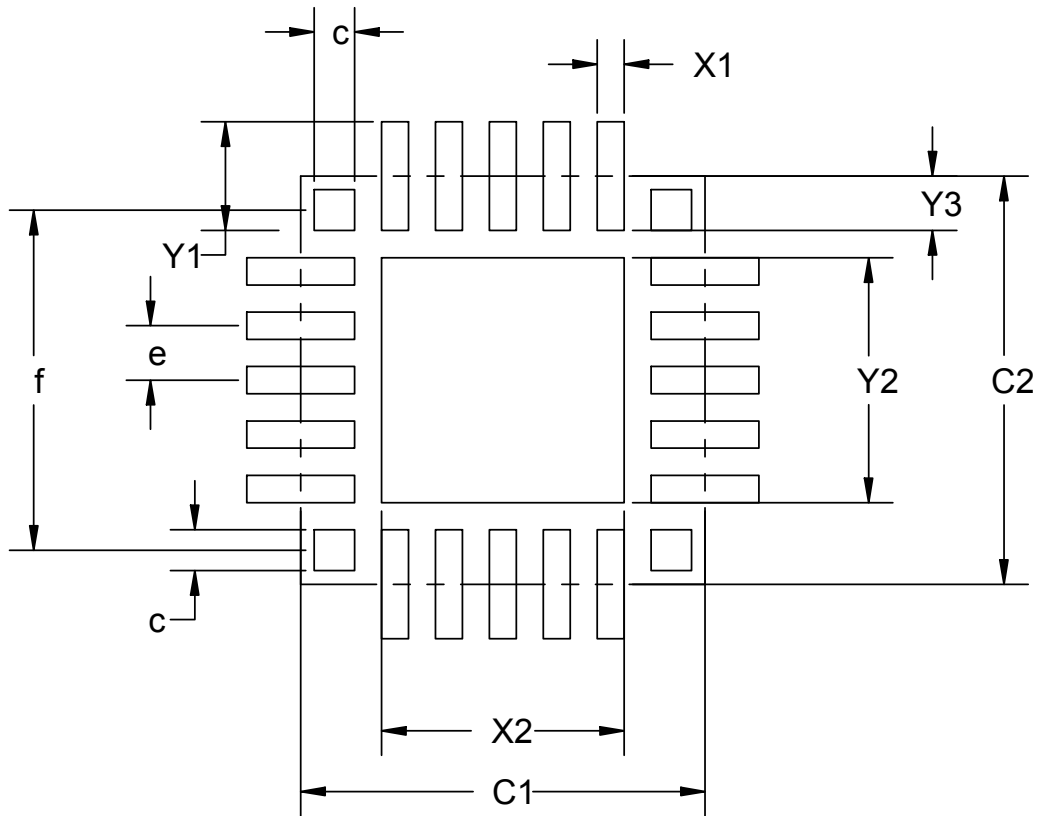


Figure 9.2. QFN24 PCB Land Pattern Drawing

Table 9.2. QFN24 PCB Land Pattern Dimensions

Dimension	Min	Max
C1		3.00
C2		3.00
e		0.4 REF
X1		0.20
X2		1.80
Y1		0.80
Y2		1.80
Y3		0.4
f		2.50 REF
c	0.25	0.35

10. QSOP24 Package Specifications

10.1 QSOP24 Package Dimensions

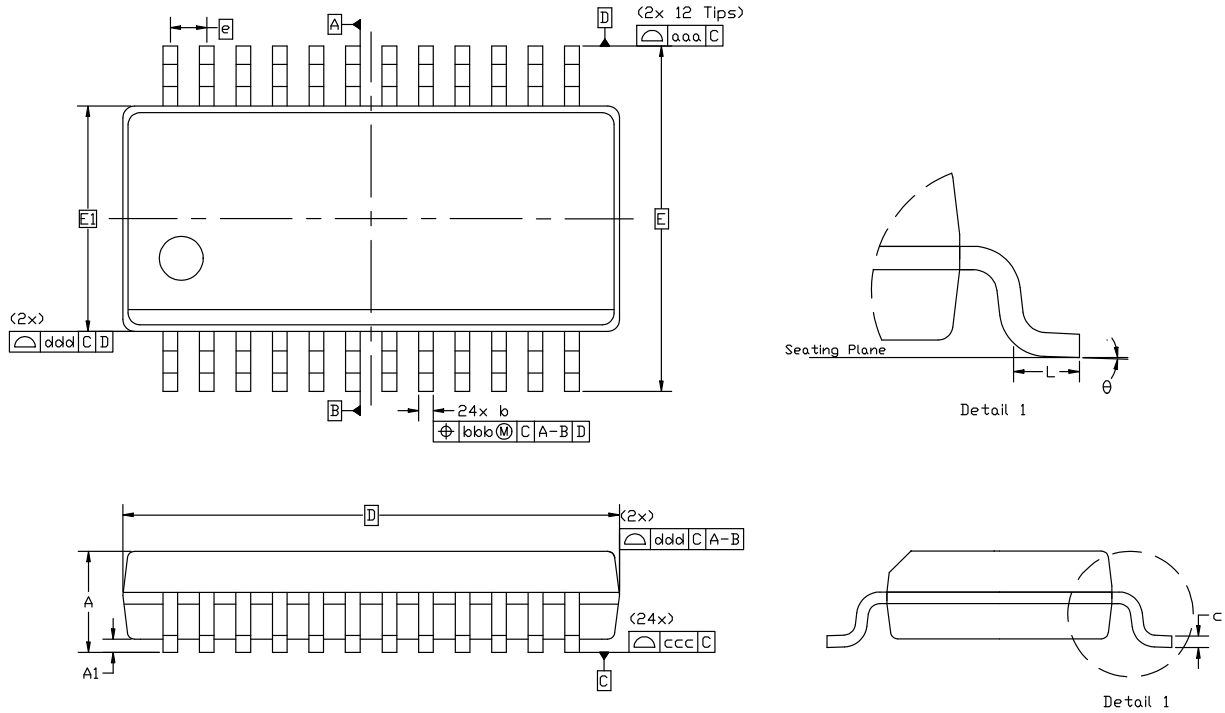


Figure 10.1. QSOP24 Package Drawing

Table 10.1. QSOP24 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.75
A1	0.10	—	0.25
b	0.20	—	0.30
c	0.10	—	0.25
D	8.65 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	0.635 BSC		
L	0.40	—	1.27
theta	0°	—	8°

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.18	
ccc		0.10	
ddd		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-137, variation AE.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.